

Four Multi Height Probe Test Unit with the RM3000



4-point probes measurement system is an electrical impedance measuring technique that uses separate pairs of current-carrying and voltage-sensing electrodes to make more accurate measurements than traditional two-terminal method. 4-point probes are used to measure resistivity of bare silicon wafer and sheet resistance of thin films.

Specifications

- 10nA to 100mA (99.999mA) current source selectable in steps to 3 decimal place resolution
- Current set numeric keypad
- 4 default preset current programs (user programmable)
- Input Impedance 1,000,000,000,000 ohms
- Input Bias current 4pA
- DVM 1300mV range and 130mV range
- 130mV accuracy
- 0.2% +/- 5uV resolution (10uV or 1uV) range
- 1300mV accuracy 0.2%+/-100uV resolution
- 100uV Ohms/Square